

## Special Issue

# Advanced Spectroscopy-Based Technologies in Soil Monitoring

### Message from the Guest Editors

Soil contamination is unfortunately a global problem and will become one of the biggest challenges to be solved in the future. Due to the fact that soil contaminations include a wide range of natural, synthetic metallic and organic compounds and minerals present in a large degree of spatial variations, one of the barriers we face today, is the lack of cost-effective and operational approaches to assess soil properties. Using modern distance methods such as proximal remote sensing and imaging spectroscopy can be the way to go to improve cost efficiency of currently used methods to determine soil geochemical property as well as concepts used for sampling strategies.

Hence in this special issue we are looking for novel solutions and approaches that open up the possibilities for quantitative prediction of diverse soil parameters in the lab as well as in a real environment. Especially we are looking for such solutions allowing synergic use of spectroscopic data covering different spectral regions (e.g., VNIR/SWIR and LWIR) and new techniques achieving higher model accuracy. Dr. Veronika Kopačková-Strnadová

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### Guest Editors

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### Deadline for manuscript submissions

closed (31 December 2020)



## Applied Sciences

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As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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### Editor-in-Chief

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